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Tables of Contents	100.00.00.00.00.00.00.00.00.00.00.00.00.	<u> </u>			
O- Journals & Magazines	Results: Journal or Magazine = JN	L Conference = CNF	Standard = STD		
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Search	No documents matched	d your query.		
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Tables of Contents		rtial name if your are unsure of the spelling.
O- Journals & Magazines	OR Select a letter to browse the	he author list
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